

*Amendments to the Claims*

The following listing of claims will replace all prior versions and/or listings of claims in the application:

1. (Currently amended): A probe coming into contact with an electrode pad of a measurement object, comprising:

a connection terminal part integrally formed and connected to a substrate;

a probe support portion; and

a contact part, the contact part comprising

an edge part having a tapered end configuration; and

a contact support part which supports the edge part and couples the edge part to the probe support part,

wherein the contact part extends from the probe support part, and wherein the edge part has a sectional configuration which shares ~~at least one~~ a side face with the contact support part and wherein the edge part has a thickness that is less than the thickness of the contact support part, and wherein the distance the edge part extends from the contact support part along the shared face is different than the distance the edge part extends from the contact support part along an opposite face.

2. (Original): The probe according to claim 1, wherein the contact part is formed of an

electrically conductive material having superior electric characteristics.

3. (Original): The probe according to claim 1, wherein the contact part is formed of a metal material having elasticity.